

December 3, 2015

Dear colleagues:

Announcement of GMA Courses 2016
Metrology in Chemistry (MiC)

March 21 (Mon) – April 1 (Fri), 2016 Daejeon, Korea

It is my great pleasure to announce that Global Metrology Academy (GMA) of KRISS is ready to offer three (3) group courses in 2016. The first one is scheduled to take place for the two weeks of March 21 – April 1, 2016 covering the key subjects of Metrology in Chemistry (MiC). We are pleased to be able to offer the one week course of Metrology and Quality (MnQ: April 25 – 29, 2016). Another technical course will present fundamental subjects of Electricity and Magnetism (EM: June 13-24, 2016).

Metrology in Chemistry (MiC): March 21 – April 1, 2016 (beginner's level)

Metrology and Quality (MnQ): April 25 – 29, 2016 (strategy course)

Metrology in Electricity and Magnetism (EM): June 13 – 24 2016 (intermediate)

Different from technical courses, the **MnQ course** will address strategic issues of metrology such as national measurement system, standardization, conformity assessment and legal metrology, QMS requirements, reference data, KC-CMC-traceability and uncertainty in measurement. *The target audience* who would most benefit from the course includes *directors of NMIs and quality managers* of metrology laboratories, among others. *High-level government officials* who are in charge of making policies on the national quality infrastructure are strongly recommended to come and enjoy the valuable programs to be delivered by professional experts in the selected subjects.

The MiC course accommodates **around 10 participants, whose applications are due by February 10, 2016**. Enclosed please find the course outline and application form, which present the provisional program, qualification and requirements for application, and the financial arrangements. There are two different categories of the tuition fees applicable to the economic performance of the applicant's country. For effectiveness, it is strongly recommended that each country could find a couple of participants at least; one from the metrology laboratory and the other from government officials. For any inquiry about applications, please feel free to contact Mr. Sangwook Seo at swseo@kriss.re.kr.

With all my best wishes!

Sincerely yours,

Gyeong-Hee Nam

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Enclosures:

1. Outline of GMA-GT-2016-01 (Metrology in Chemistry)
2. Application/Nomination Form
3. Overview of GMA Courses 2016

cc: Mr. Sangwook Seo, swseo@kriss.re.kr